

Accelerating transient fault injection campaigns by using Dynamic HDL Slicing

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC), 29-30 October 2019, Helsinki, Finland : proceedings in IEEE Xplore 2019 / 7 p. : ill <https://doi.org/10.1109/NORCHIP.2019.8906932>

Automated identification of application-dependent safe faults in automotive systems-on-a-chips

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim;** Sauer, Christian Electronics 2022 / art. 319 <https://doi.org/10.3390/electronics11030319> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Combining fault analysis technologies for ISO26262 functional safety verification

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri;** Hamdioui, Said; Sauer, Christian 2019 IEEE 28th Asian Test Symposium (ATS) : 10–13 December 2019, Kolkata, India : proceedings 2019 / p. 129–134 : ill <https://doi.org/10.1109/ATS47505.2019.00024>

Determined-safe faults identification : a step towards ISO26262 hardware compliant designs

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Efficient fault injection based on dynamic HDL slicing technique

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Efficient methodology for ISO26262 functional safety verification

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Enabling cross-layer reliability and functional safety assessment through ML-based compact models

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Improving the confidence level in functional safety simulation tools for ISO 26262

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Representing gate-level SET faults by multiple SEU faults on RT-level

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Special session : AutoSoC - a suite of open-source automotive SoC benchmarks

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